



LIST OF PUBLICATIONS CITED BY APPLICANT	<u>Atty. Docket No.</u> 0553-0323.01	<u>Serial No.</u> 10/643,690
	<u>Applicant</u> Yoshiyuki KUROKAWA et al	
	<u>Filing Date</u> August 19, 2003	<u>Group</u> 2815

#### U. S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE

#### FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE

#### OTHER PRIOR ART - NON-PATENT LITERATURE DOCUMENTS (Including Author, Title, Date, Pertinent Pages)

922	CHU, S. et al, "The Effect of Trench-Gate-Oxide Structure on EPROM Device Operation," IEEE Electron Device Letters, vol. 9, no. 6, pp. 284-286, June (1988).
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EXAMINER:	<i>J. Schantz</i>	DATE CONSIDERED:	<i>2/7/05</i>
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